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Irish Standard
I.S. EN 61124:2012

Reliability testing - Compliance tests for constant failure rate and constant failure intensity

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EUROPEAN STANDARD

NORME EUROPÉENNE

EUROPÄISCHE NORM

EN 61124

August 2012

ICS 03.120.30; 19.020; 21.020

Supersedes EN 61124:2006

English version

Reliability testing - Compliance tests for constant failure rate and constant failure intensity

(IEC 61124:2012)

Essais de fiabilité - Plan d'essais de conformité d'un taux de défaillance constant et d'une intensité de défaillance constante (CEI 61124:2012)

Prüfungen der Funktionsfähigkeit - Prüfpläne für konstante Ausfallrate und konstante Ausfalldichte (IEC 61124:2012)

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Ref. No. EN 61124:2012 E

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Foreword

The text of document 56/1461/FDIS, future edition 3 of IEC 61124, prepared by IEC/TC 56 "Dependablility" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61124:2012.

The following dates are fixed:

• latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2013-03-27
• latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2015-06-27

This document supersedes EN 61124:2006.

EN 61124:2012 includes the following significant technical changes with respect to EN 61124:2006:

- a number of new test plans have been added based on the Russian standard GOST R 27.402, and it is intended to align the new edition of MIL-HDBK-781 with this edition. Algorithms for optimizing test plans using a spreadsheet program are given and a number of optimized test plans are listed. Furthermore, emphasis is laid on the fact that the test should be repeated following design changes;
- discrepancies in test plans A, B as well as Annexes A and B that originated in IEC 60605-7, now withdrawn, have been corrected so these test plans differ from those given in previous edition of EN 61124. As requested by the National committees, mathematical background material and spreadsheet program information has been moved to informative annexes. In addition, the symbol lists have been divided, so that some annexes have separate lists of symbols;
- guidance on how to choose test plans has been added as well as guidance on how to use spreadsheet programs to create them. Test plans A.1 to A.9 and B.1 to B.13 have been corrected;
- Subclauses 8.1, 8.2, 8.3, Clause 9, Annex C, Clauses G.2, I.2, I.3 and Annex J are unchanged, except for updated terminology and references;
- corrections to the second edition proposed by National Committees have been implemented.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

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Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

Publication	Year	Title	EN/HD	Year
IEC 60050-191	-	International Electrotechnical Vocabulary (IEV) - Chapter 191: Dependability and quality of service	-	-
IEC 60300-3-5	2001	Dependability management - Part 3-5: Application guide - Reliability test conditions and statistical test principles	-	-
IEC 60605-2	-	Equipment reliability testing - Part 2: Design of test cycles	-	-
IEC 60605-4	2001	Equipment reliability testing - Part 4: Statistical procedures for exponential distribution - Point estimates, confidence intervals, prediction intervals and tolerance intervals	-	-
IEC 60605-6	-	Equipment reliability testing - Part 6: Tests for the validity and estimation of the constant failure rate and constant failure intensity	-	-
IEC 61123	1991	Reliability testing - Compliance test plans for success ratio	-	-

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IEC 61124

Edition 3.0 2012-05

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